



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Tikashi AKATSU *et al.* Confirmation No.: 2653  
Application No: 10/663,917 Group Art Unit: 2811  
Filing Date: September 17, 2003 Examiner: Not Assigned  
For: WAFER WITH A RELAXED USEFUL Attorney Docket No.: 4717-8900  
LAYER AND METHOD OF FORMING THE  
WAFER

**SECOND INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Arlexandria, Virginia 22313-1450

Sir:

Pursuant to Applicant's duty of disclosure under 37 C.F.R. § 1.56, enclosed is a Form PTO-1449 which lists fifteen (15) references for the Examiner's review. Also enclosed is a copy of the French and International Search Reports from the corresponding foreign applications on which the references were cited.

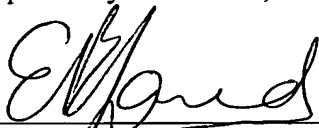
Copies of non-U.S. patent references B1-B2 and C1-C2 are enclosed herewith. Copies of U.S. patent references A1-A11 will be provided if the Examiner so requests.

It is respectfully requested that the references be made of record in this application by the Examiner's completion and return of the attached Form PTO-1449.

This Second Information Disclosure Statement is being submitted under 37 C.F.R. §1.97(b)(3), prior to the mailing of a first Office Action on the merits; thus no fee is believed to be required. Should any fees be required, however, please charge such fees to Winston & Strawn LLP Deposit Account No. 50-1814.

Respectfully submitted,

April 27, 2004  
\_\_\_\_\_  
Date

  
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E. Bradley Gould (Reg. No. 41,792)  
For: Allan A. Fanucci (Reg. No. 30,256)

**WINSTON & STRAWN LLP**  
**Customer No. 28765**

202-371-5771

<b>LIST OF REFERENCES CITED BY APPLICANT</b> <b>Form PTO-1449</b> <i>(Use several sheets if necessary)</i>					ATTY. DOCKET NO.: <b>4717-8900</b>		APPLICATION NO.: <b>10/663,917</b>	
<div style="position: relative; height: 100px;"> <div style="position: absolute; top: 0; left: 0; width: 100%; height: 100%; border: 1px solid black; border-radius: 50%; text-align: center; line-height: 100px; font-size: 24px; font-weight: bold;">             O I P E              APR 27 2004              PATENT &amp; TRADEMARK OFFICE           </div> </div>					APPLICANT: <b>Tukeshi AKATSU et al.</b>		FILING DATE: <b>September 17, 2003</b>	
Sheet 1 of 1					GROUP: <b>2811</b>			
<b>U.S. PATENT DOCUMENTS</b>								
*EXAMINER INITIAL	CITE NO.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	A1	6,100,166	08/2000	Sakaguchi et al.	438	455		
	A2	2002/0125497 A1	09/2002	Fitzgerald	257	191		
	A3	2002/0123183 A1	09/2002	Fitzgerald	438	199		
	A4	6,521,041 B2	02/2003	Wu et al.	117	94		
	A5	6,534,382 B1	03/2003	Sakaguchi et al.	438	455		
	A6	2003/0077867	04/2003	Fitzgerald	438	285		
	A7	6,593,641 B1	07/2003	Fitzgerald	257	616		
	A8	2003/0203547 A1	10/2003	Sakaguchi et al.	438	151		
	A9	6,646,322 B2	11/2003	Fitzgerald	257	531		
	A10	2004/0000268 A1	01/2004	Wu et al.	11	94		
	A11	6,677,192 B1	01/2004	Fitzgerald	438	172		
<b>FOREIGN PATENT DOCUMENTS</b>								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	B1	WO 99/53539 A	10/1999	WIPO				
	B2	WO 02/071495 A	12/2002	WIPO				
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)</b>								
	C1	Cheng, Z-Y et al., "SiGe-On-Insulator (SGOI): Substrate Preparation and MOSFET Fabrication for Electron Mobility Evaluation," IEEE International SOI Conference, pp. 13-14, October 2001						
	C2	Tong, Q.Y. et al., "Semiconductor Wafer Bonding" (extracts), Science and Technology, Interscience Technology, November 1998						
<b>EXAMINER</b>					<b>DATE CONSIDERED</b>			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with <b>MPEP 609</b> . Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								